



**ALPHA & OMEGA**  
SEMICONDUCTOR

**AOD496**

**N-Channel Enhancement Mode Field Effect Transistor**

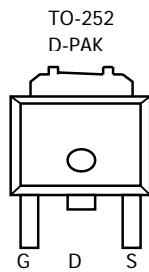


### General Description

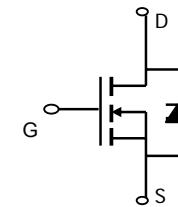
The AOD496 uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge. This device is suitable for use as a high side switch in SMPS and general purpose applications. Standard Product AOD496 is Pb-free (meets ROHS & Sony 259 specifications). AOD496L is a Green Product ordering option. AOD496 and AOD496L are electrically identical.

### Features

$V_{DS}$  (V) = 30V  
 $I_D$  = 62A ( $V_{GS}$  = 10V)  
 $R_{DS(ON)} < 9.5m\Omega$  ( $V_{GS}$  = 10V)  
 $R_{DS(ON)} < 16m\Omega$  ( $V_{GS}$  = 4.5V)



Top View  
Drain Connected to Tab



### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>B</sup>	$T_C=25^\circ C$	62	A
$T_C=100^\circ C$	$I_D$	44	
Pulsed Drain Current	$I_{DM}$	120	
Avalanche Current <sup>C</sup>	$I_{AR}$	30	A
Repetitive avalanche energy $L=0.3mH$ <sup>C</sup>	$E_{AR}$	135	mJ
Power Dissipation <sup>B</sup>	$T_C=25^\circ C$	62.5	W
$T_C=100^\circ C$	$P_D$	31	
Power Dissipation <sup>A</sup>	$T_A=25^\circ C$	2.5	W
$T_A=70^\circ C$	$P_{DSM}$	1.6	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 175	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$t \leq 10s$	$R_{\theta JA}$	15	°C/W
Maximum Junction-to-Ambient <sup>A</sup>	Steady-State	$R_{\theta JA}$	41	°C/W
Maximum Junction-to-Case <sup>C</sup>	Steady-State	$R_{\theta JC}$	2	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=24\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		1		$\mu\text{A}$
				5		
$I_{GSS}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS} = \pm 20\text{V}$			0.1	$\mu\text{A}$
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1	1.9	2.5	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	120			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=20\text{A}$ $T_J=125^\circ\text{C}$		7.7	9.5	$\text{m}\Omega$
			11.0			
		$V_{GS}=4.5\text{V}, I_D=20\text{A}$		13	16.0	$\text{m}\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=20\text{A}$		40		S
$V_{SD}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.73	1.0	V
$I_S$	Maximum Body-Diode Continuous Current				46	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		1000	1200	pF
$C_{oss}$	Output Capacitance			340		pF
$C_{rss}$	Reverse Transfer Capacitance			100		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		1.3	2.0	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, I_D=20\text{A}$		18	23	nC
$Q_g(4.5\text{V})$	Total Gate Charge			8.5		nC
$Q_{gs}$	Gate Source Charge			3.1		nC
$Q_{gd}$	Gate Drain Charge			4.8		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=0.75\Omega, R_{\text{GEN}}=3\Omega$		5.6		ns
$t_r$	Turn-On Rise Time			5.5		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			18.5		ns
$t_f$	Turn-Off Fall Time			5		ns
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=20\text{A}, dI/dt=100\text{A}/\mu\text{s}$		29		ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=20\text{A}, dI/dt=100\text{A}/\mu\text{s}$		24		nC

A: The value of  $R_{\text{GJA}}$  is measured with the device in a still air environment with  $T_A=25^\circ\text{C}$ .

B. The power dissipation  $P_D$  is based on  $T_J(\text{MAX})=175^\circ\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature  $T_J(\text{MAX})=175^\circ\text{C}$ .

D. The  $R_{\text{GJA}}$  is the sum of the thermal impedance from junction to case  $R_{\text{JC}}$  and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300 ms pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_J(\text{MAX})=175^\circ\text{C}$ .

G. These tests are performed with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

H. Surface mounted on a 1 in 2 FR-4 board with 2oz. Copper.

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## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

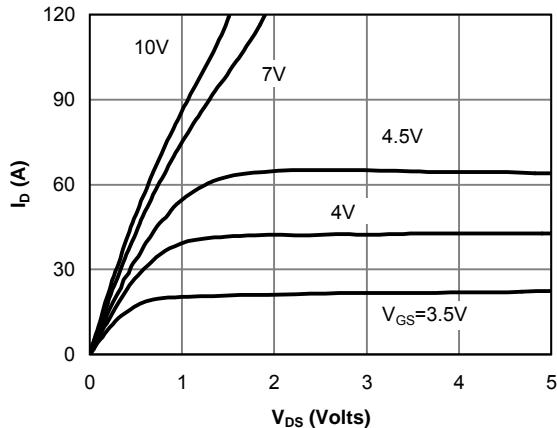


Figure 1: On-Region Characteristics

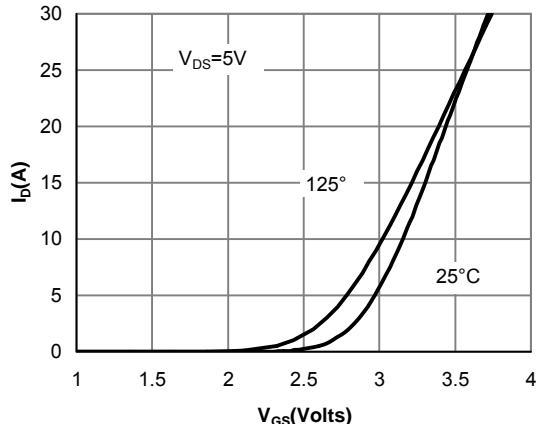


Figure 2: Transfer Characteristics

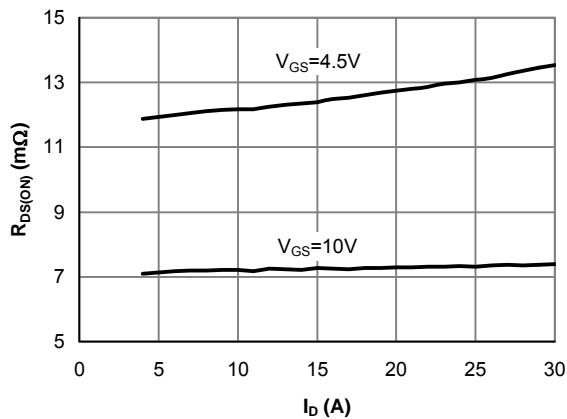


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

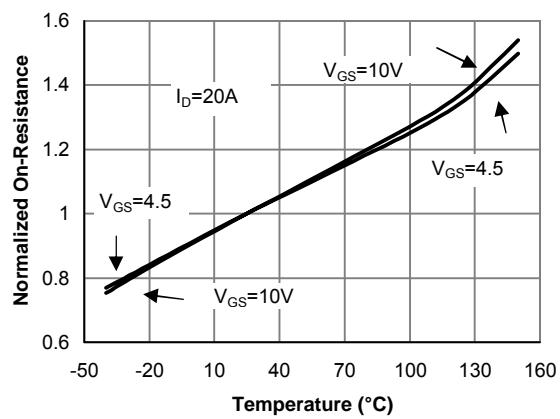


Figure 4: On-Resistance vs. Junction Temperature

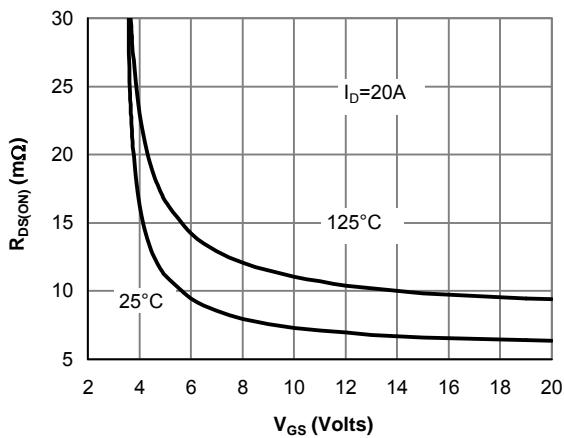


Figure 5: On-Resistance vs. Gate-Source Voltage

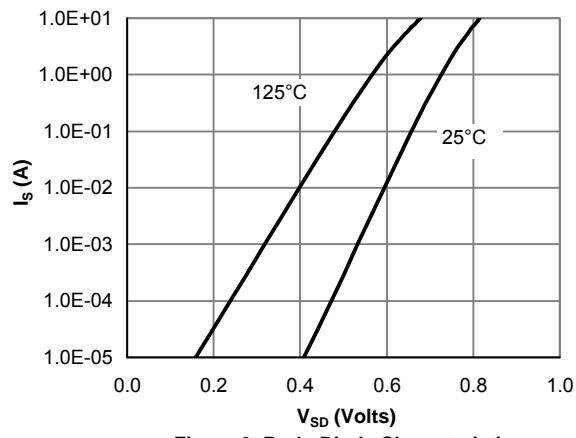


Figure 6: Body-Diode Characteristics

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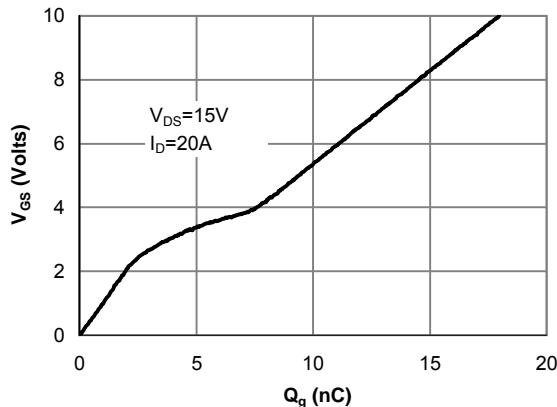


Figure 7: Gate-Charge Characteristics

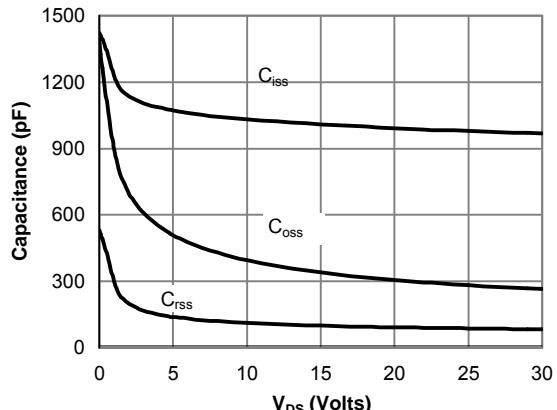


Figure 8: Capacitance Characteristics

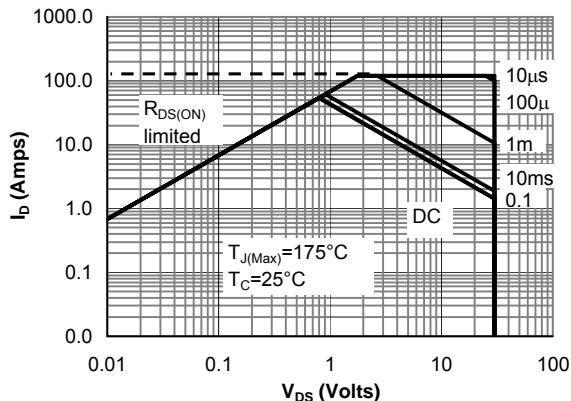


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

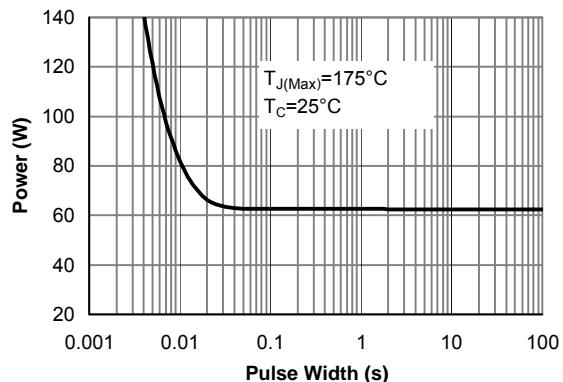


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

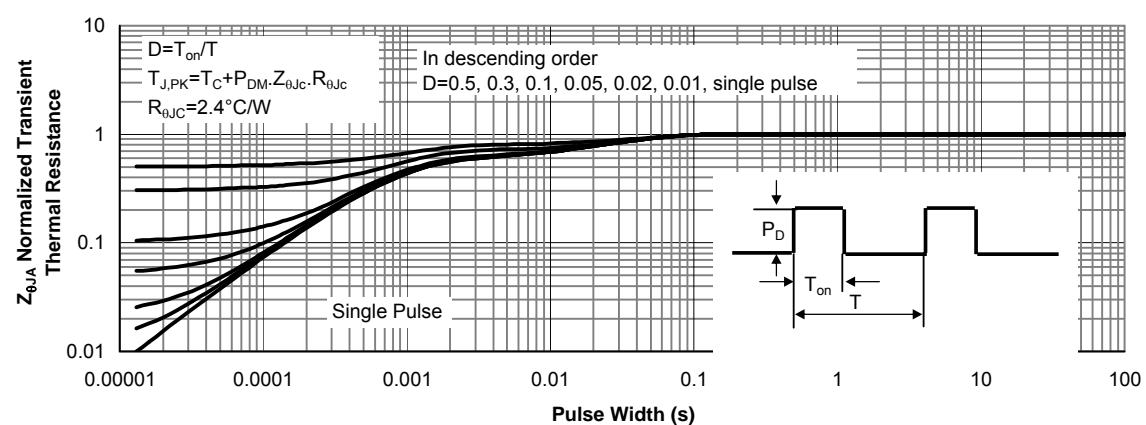


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

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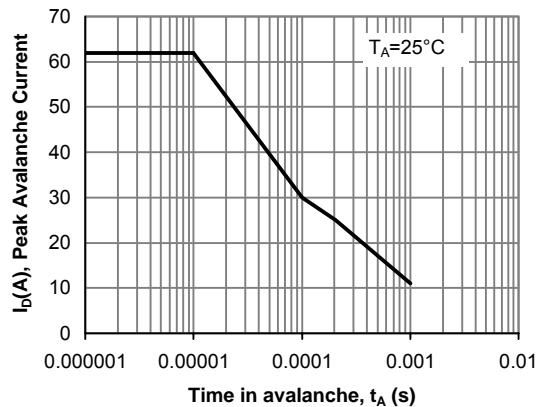


Figure 12: Single Pulse Avalanche capability

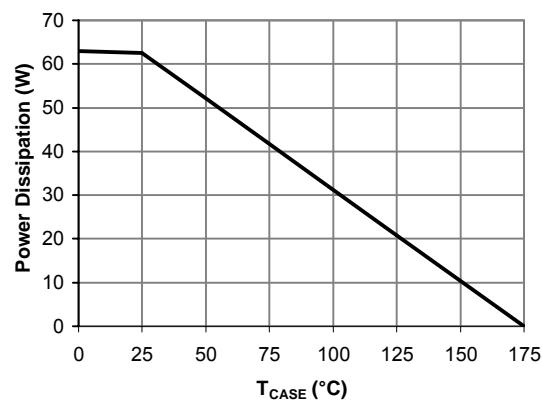


Figure 13: Power De-rating (Note B)

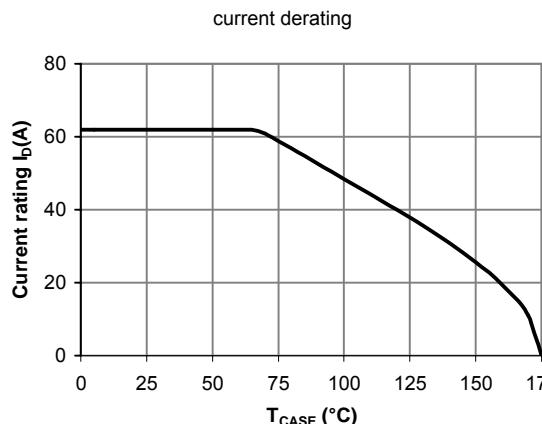


Figure 14: Current De-rating (Note B)

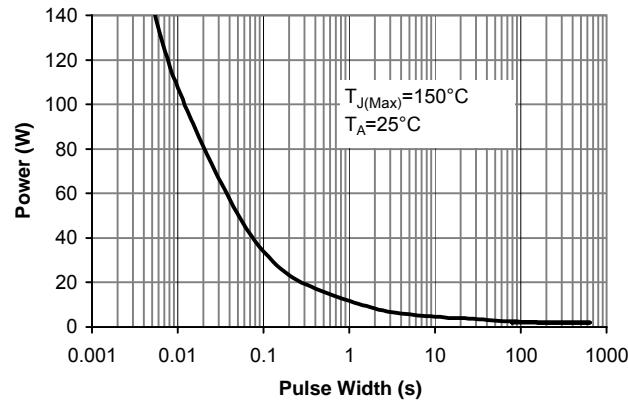


Figure 15: Single Pulse Power Rating Junction-to-Ambient (Note H)

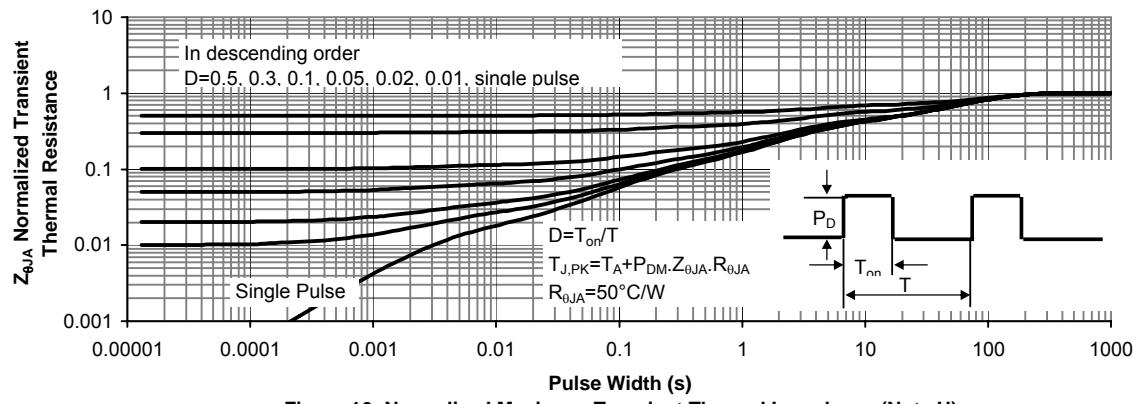


Figure 16: Normalized Maximum Transient Thermal Impedance (Note H)